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(12) United States Design Patent
Matsumiya et al.

(10) **Patent No.: US D848,882 S**
(45) **Date of Patent: ** May 21, 2019**

(54) **HARDNESS TESTER**

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(73) Assignee: **MITUTOYO CORPORATION**, Kawasaki (JP)

(**) Term: **15 Years**

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(30) **Foreign Application Priority Data**

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(51) **LOC (11) Cl.** **10-04**
(52) **U.S. Cl.**
USPC **D10/83**; D10/63
(58) **Field of Classification Search**
USPC D10/63, 83, 84, 85
CPC G01N 3/40; G01N 3/405; G01N 3/42; G01N 3/44; G01N 3/46; G01N 3/48; G01N 3/50; G01N 3/52; G01N 3/54; G01N 3/00; G01N 3/08; G01N 3/10; G01N 3/12; G01N 3/14; G01N 3/16; G01N 3/30; G01N 3/32; G01B 2203/00; G01B 2203/0001; G01B 2203/0003; G01B 2203/0005; G01B 2203/001; G01B 2203/0012; G01B 2203/0014; G01B 2203/0016; G01B 2203/0017; G01B 2203/0019; G01B 2203/0076
See application file for complete search history.

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(74) *Attorney, Agent, or Firm* — Oliff PLC

(57) **CLAIM**

The ornamental design for a hardness tester, as shown and described.

DESCRIPTION

FIG. **1** is a front, right-side, top perspective view of the hardness tester;
FIG. **2** is a front elevational view thereof;
FIG. **3** is a top plan view thereof;
FIG. **4** is a right-side elevational view thereof;
FIG. **5** is a left-side elevational view thereof;
FIG. **6** is a rear elevational view thereof;
FIG. **7** is a bottom plan view thereof; and,
FIG. **8** is an enlarged view of the area bounded by arrow **8'** and **8"** in FIG. **4**.
The broken lines depict unclaimed parts of the hardness tester, and thus form no part of the claimed design. The

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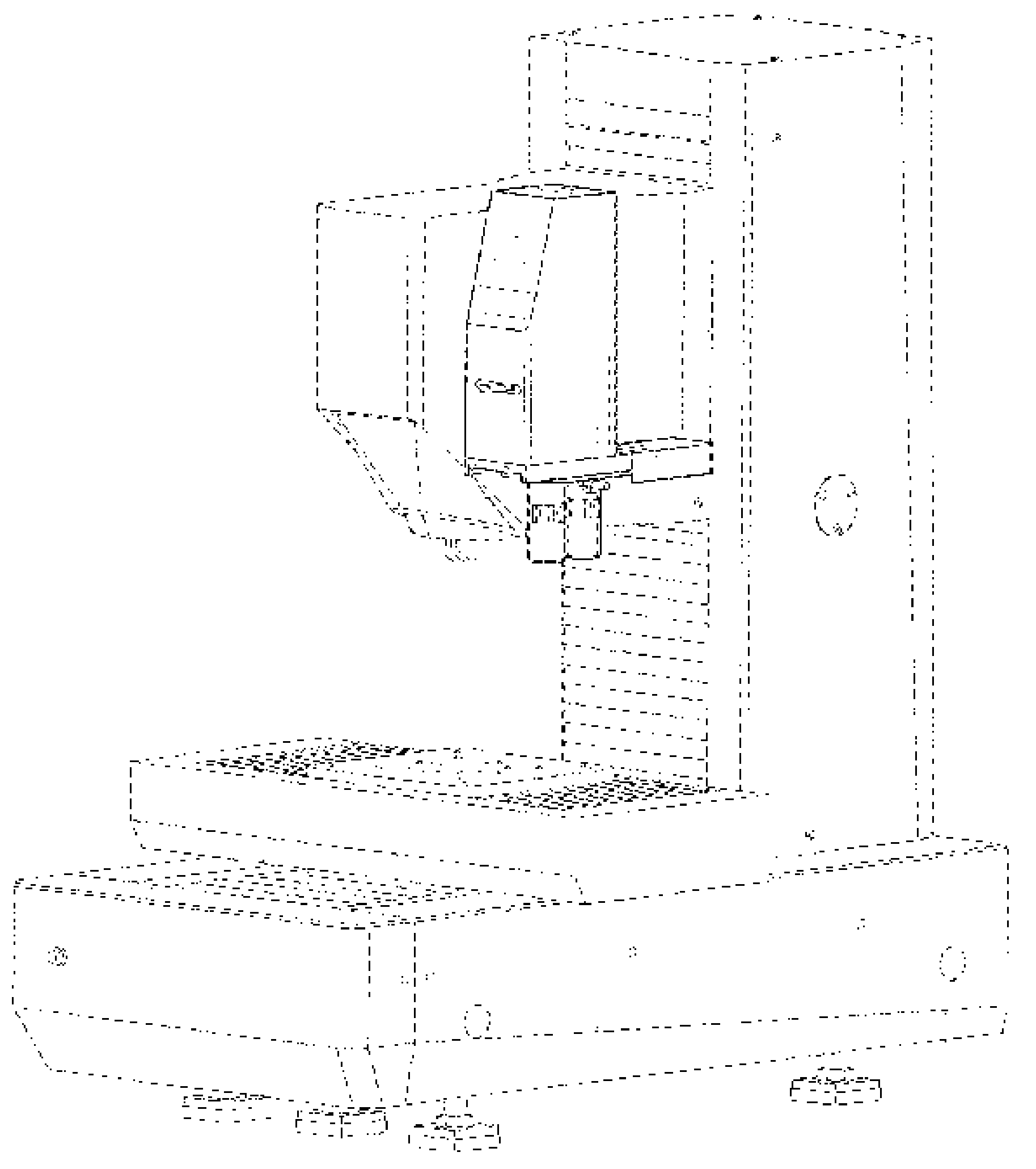

dot-dot-dash chain lines depict boundaries of the enlarged area, and thus form no part of the claimed design.

1 Claim, 8 Drawing Sheets

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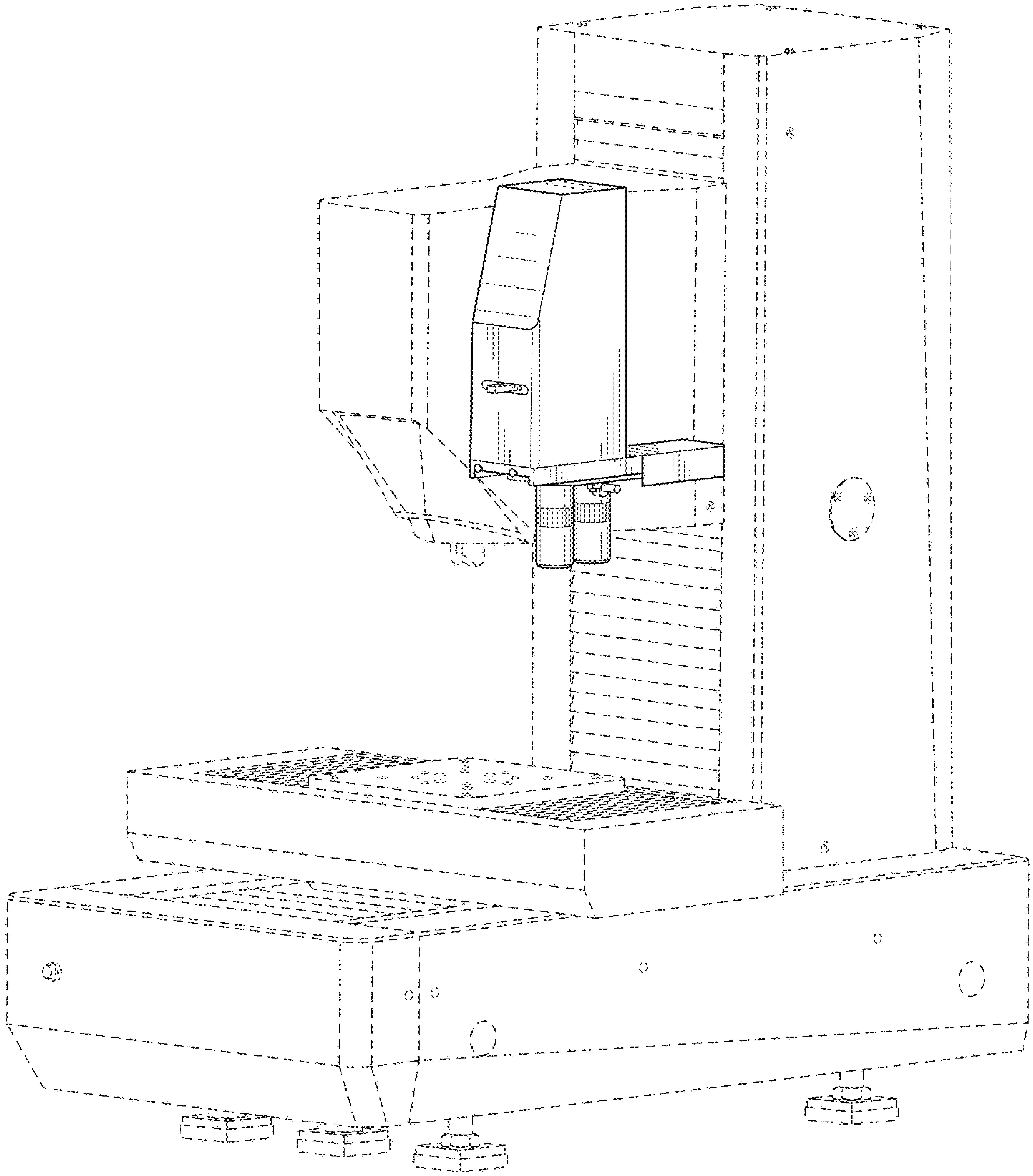

FIG. 1

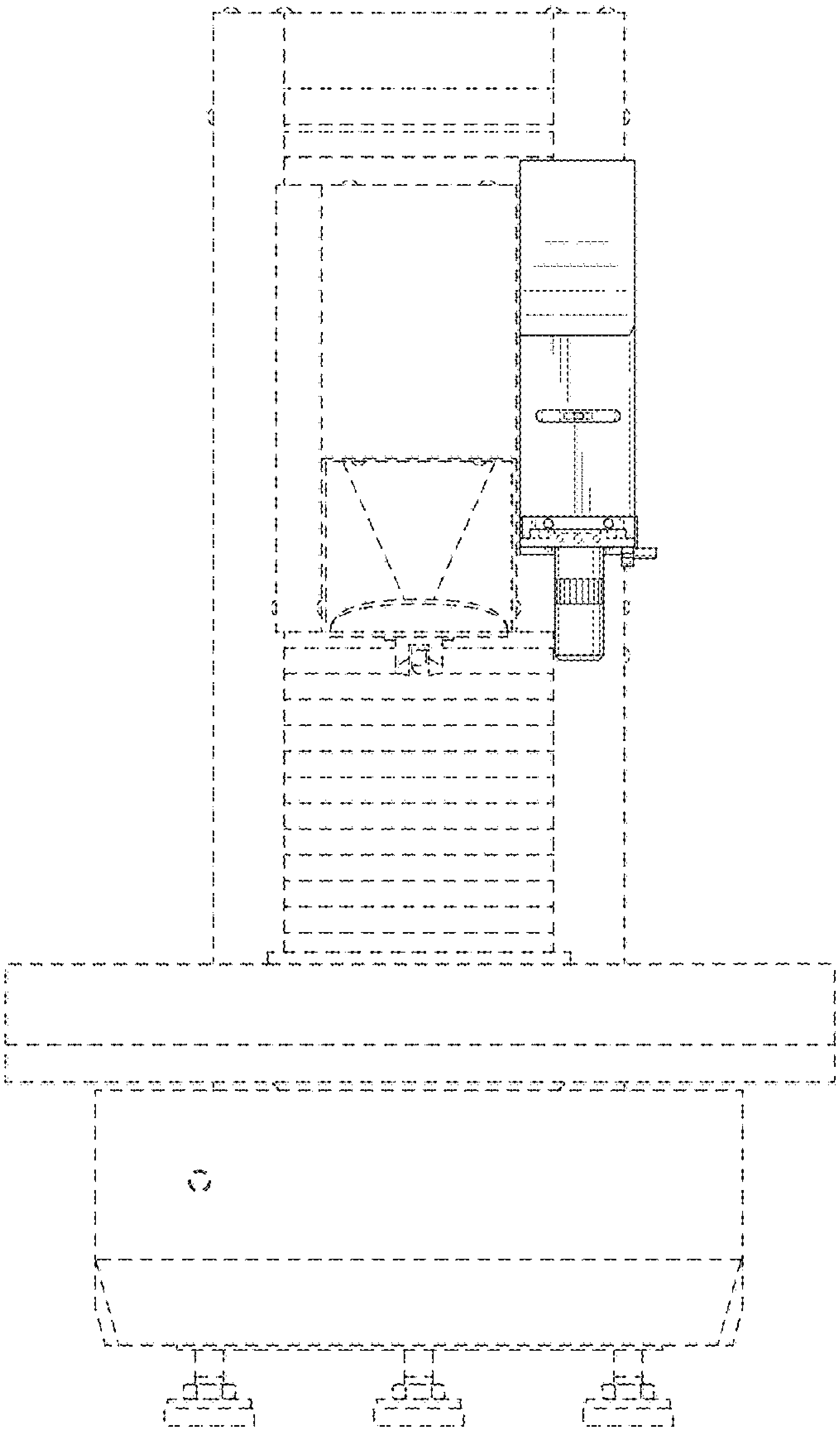

FIG. 2

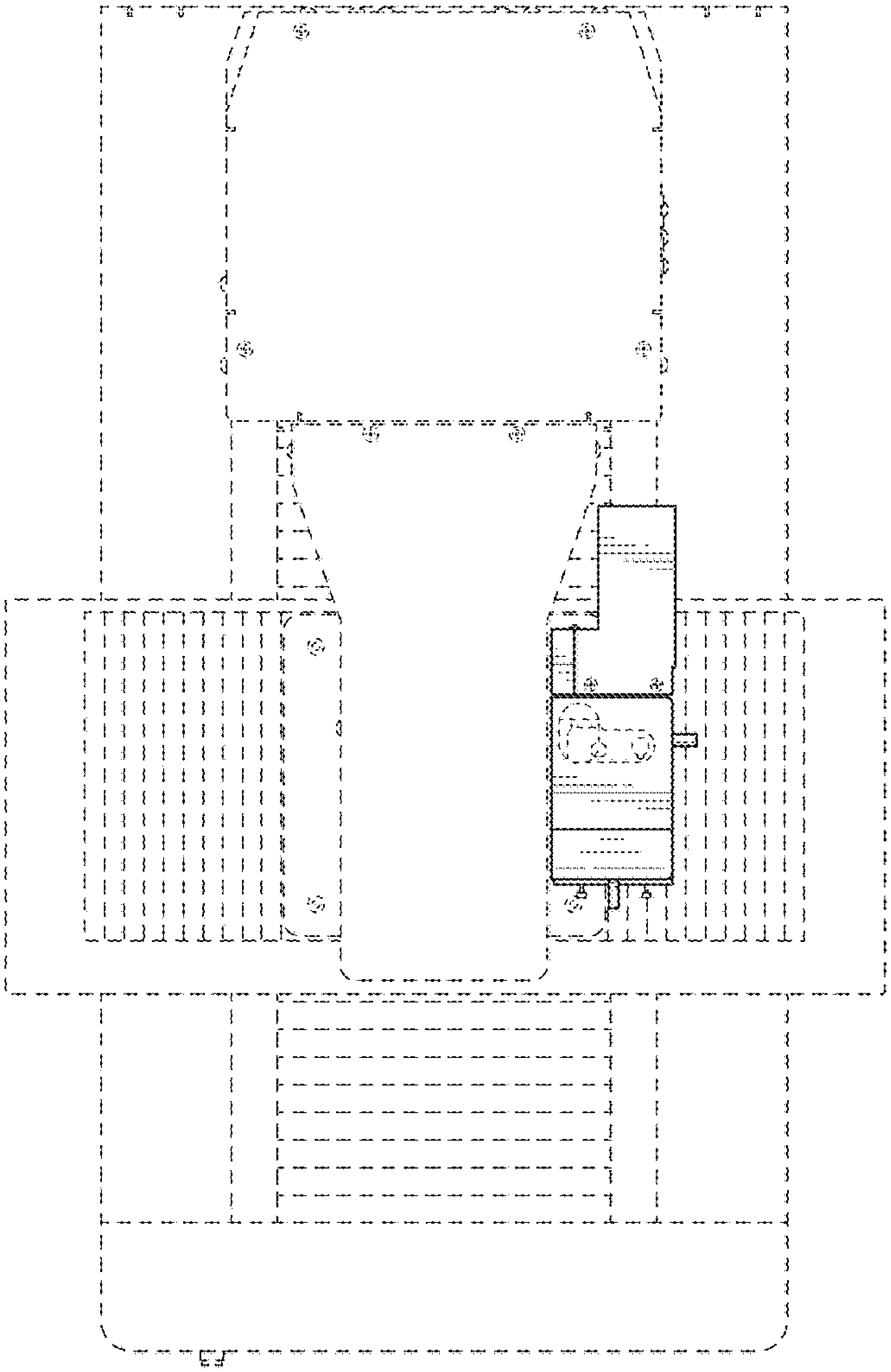

FIG. 3

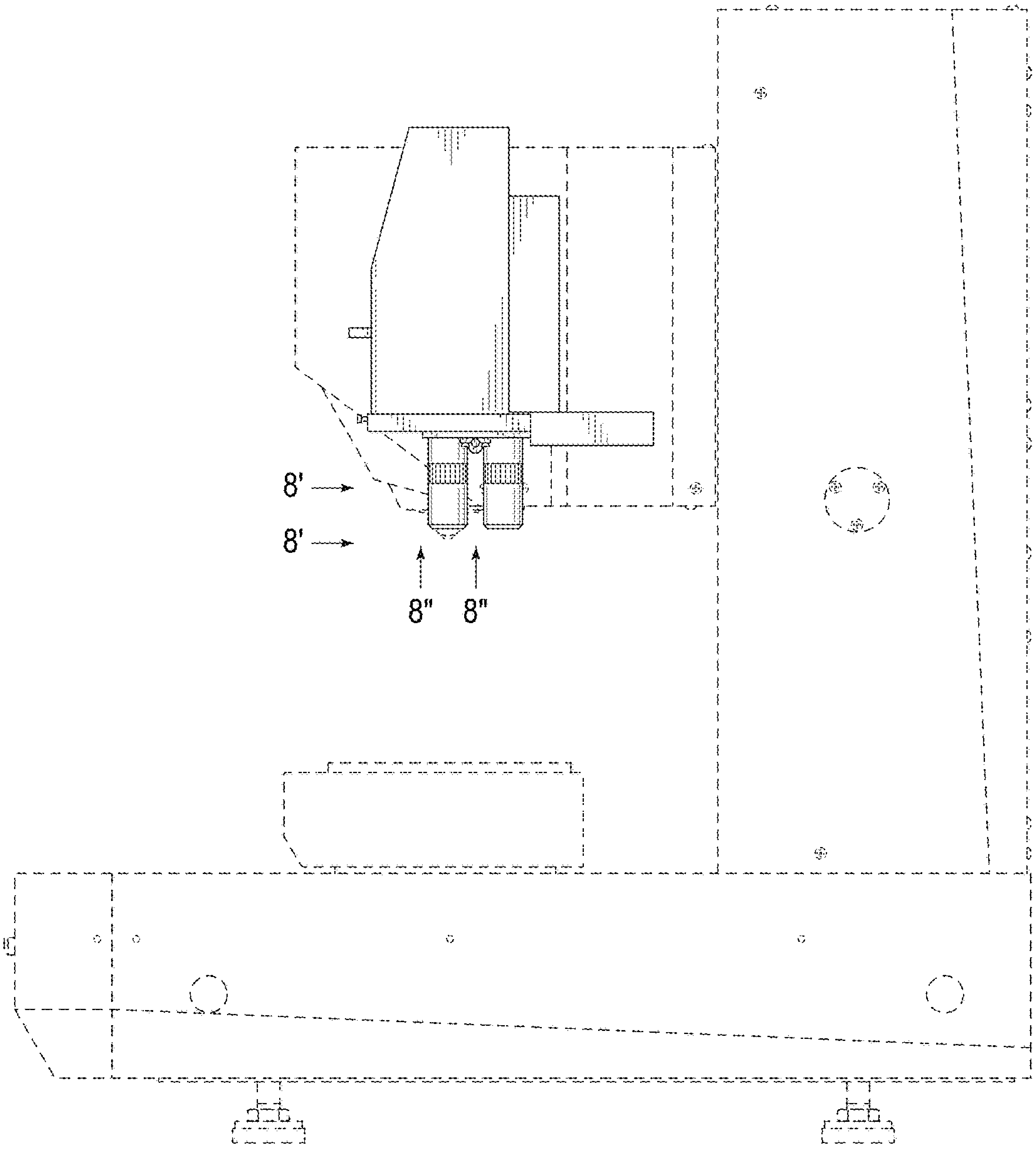

FIG. 4

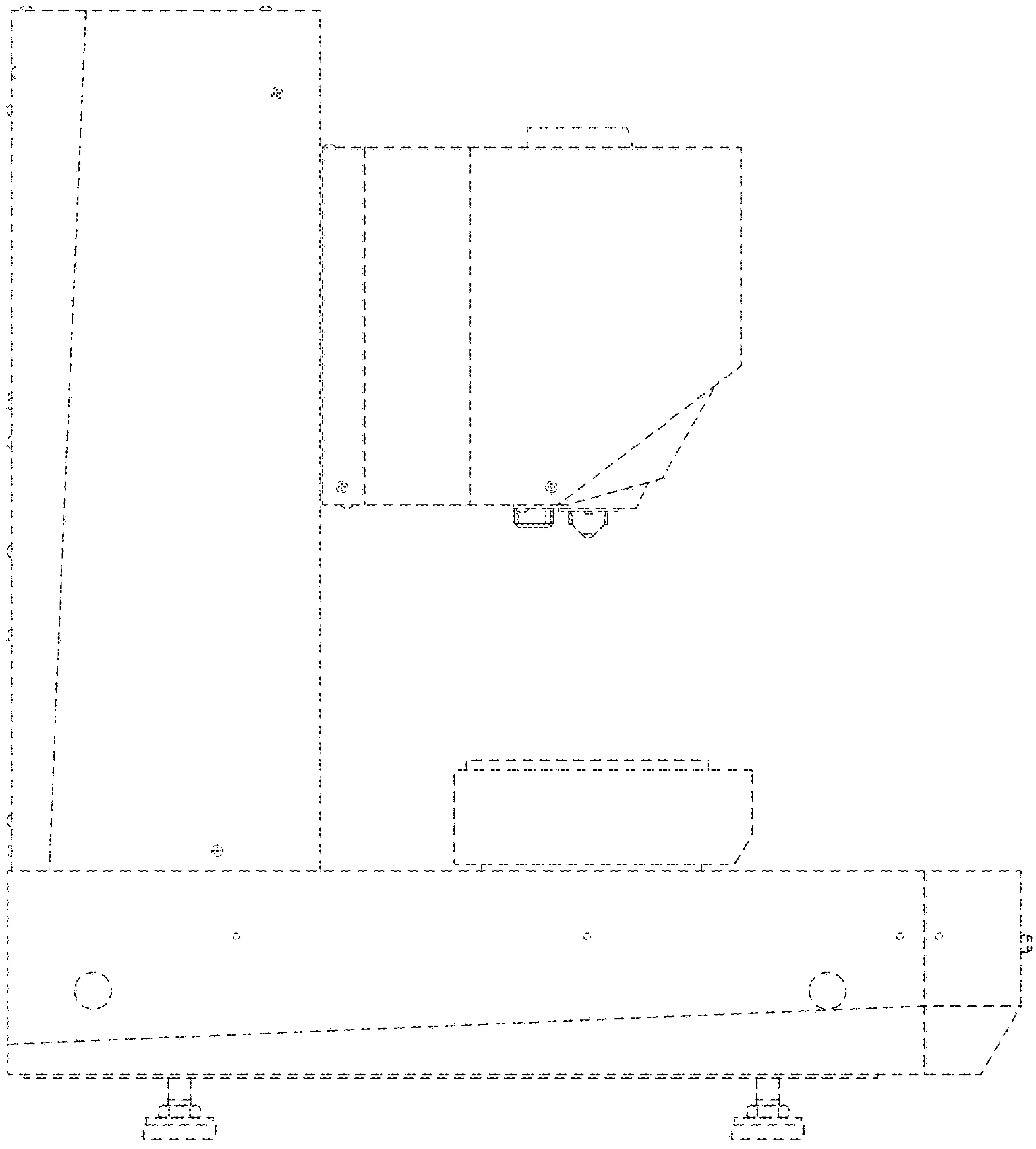

FIG. 5

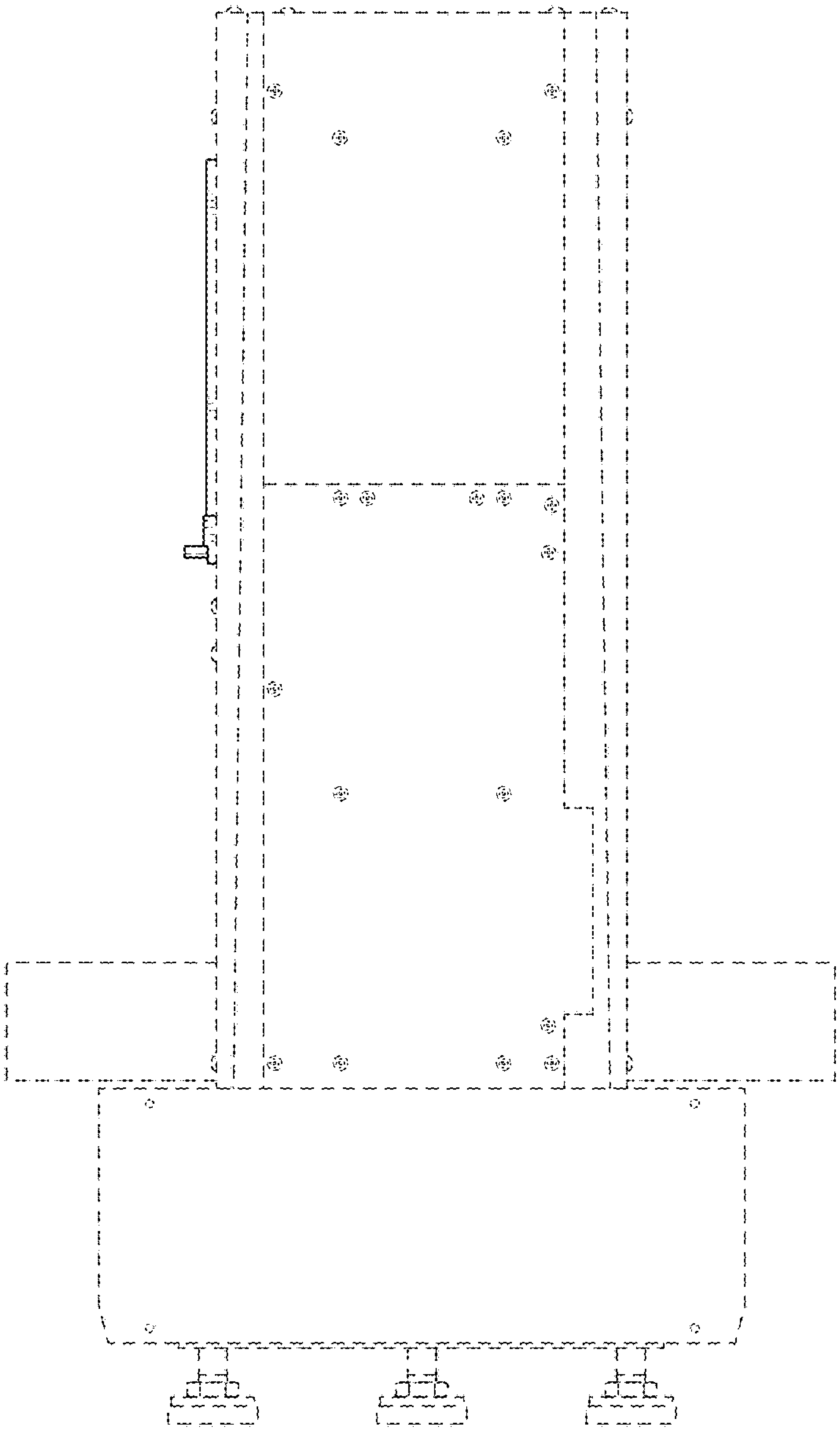

FIG. 6

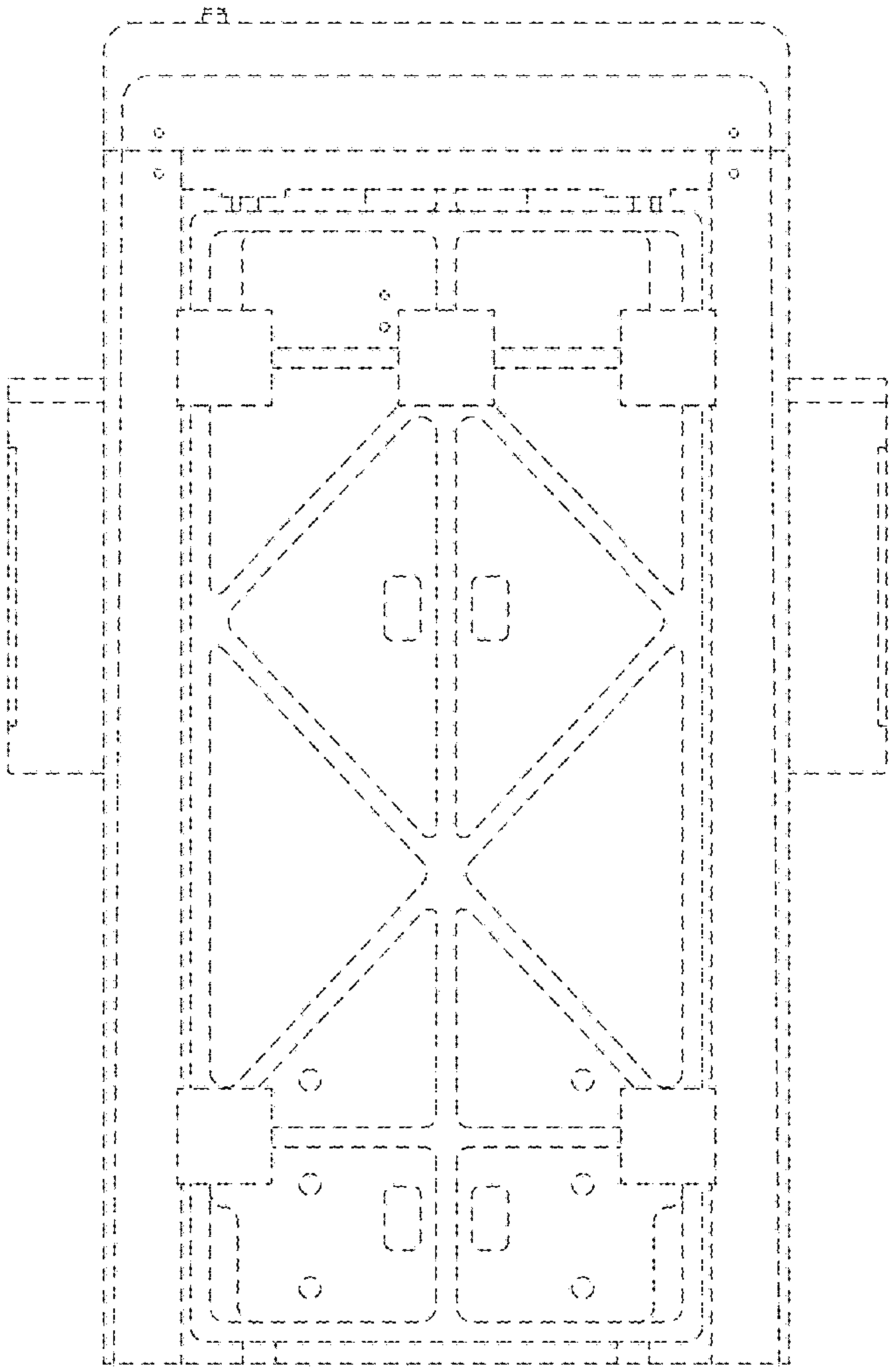

FIG. 7

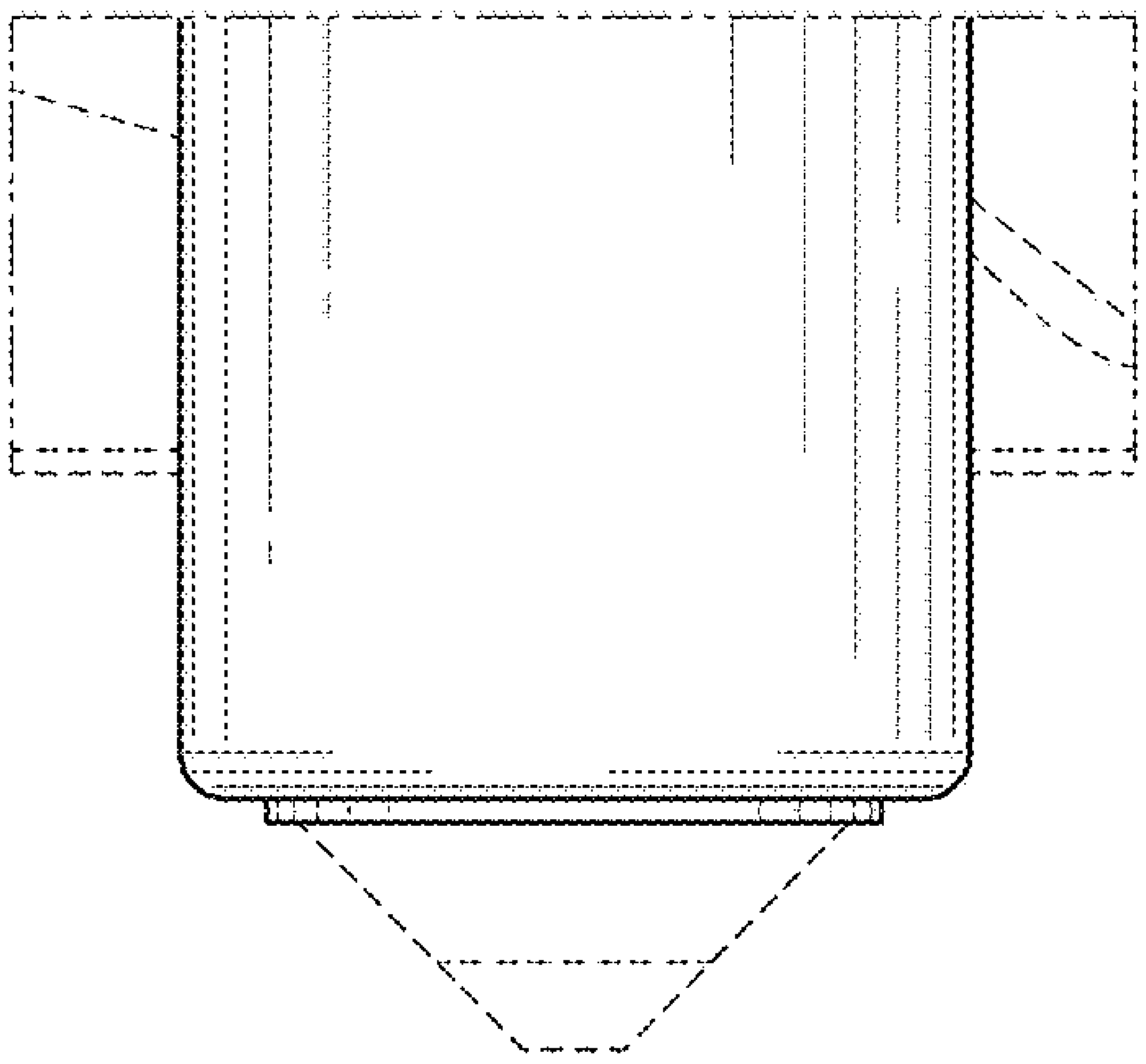

FIG. 8